

**Search Notes**

Application/Control No.

10/710,456

Examiner

Huyen Le.

Applicant(s)/Patent under  
Reexamination

KEMP ET AL.

Art Unit

3751

**SEARCHED**

Class	Subclass	Date	Examiner
4	576.1 577.1	7/19/2007	HL
	updated		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PGPUB		7/19/2007	HL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR